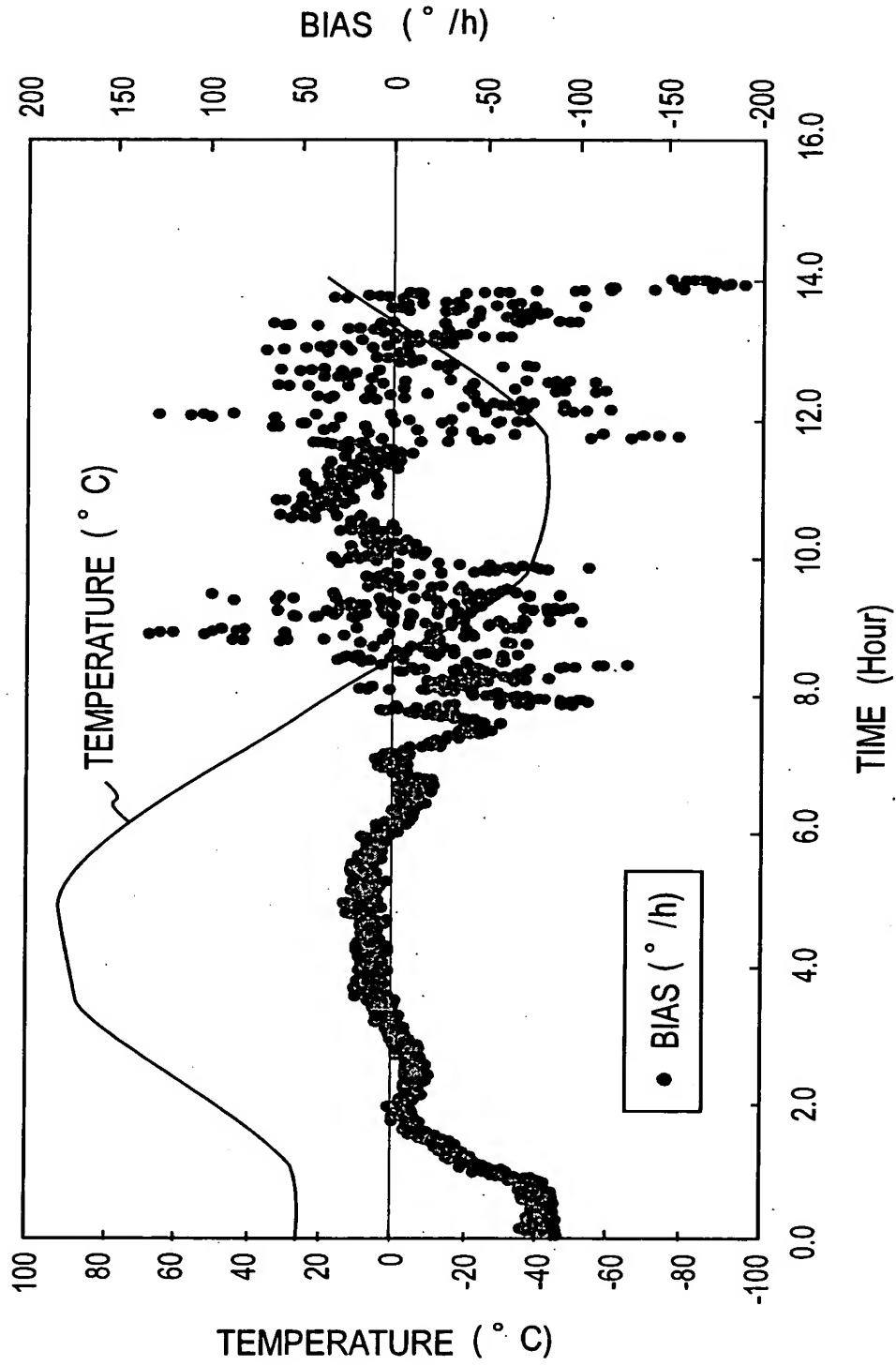
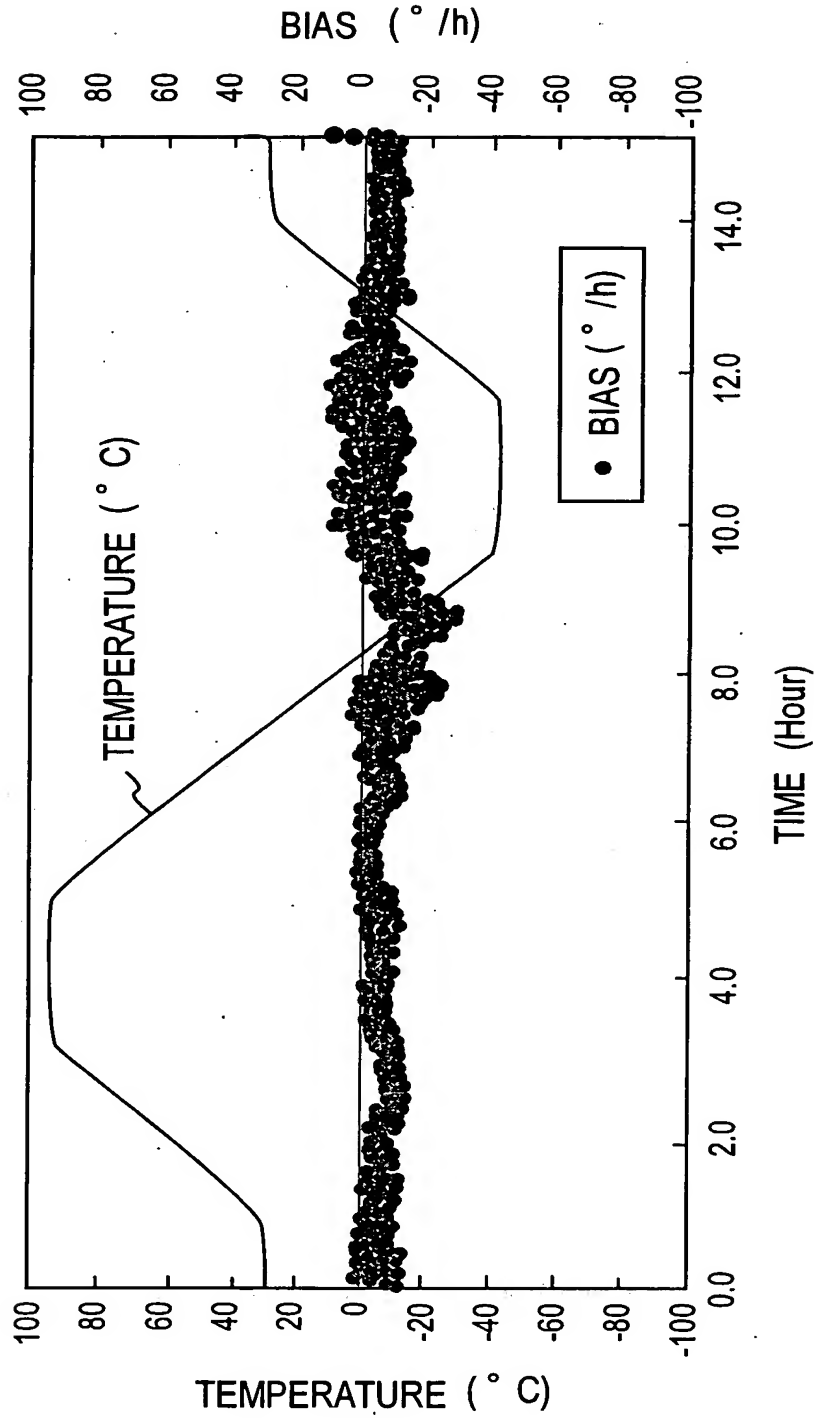


FIG. 1
 PRIOR ART



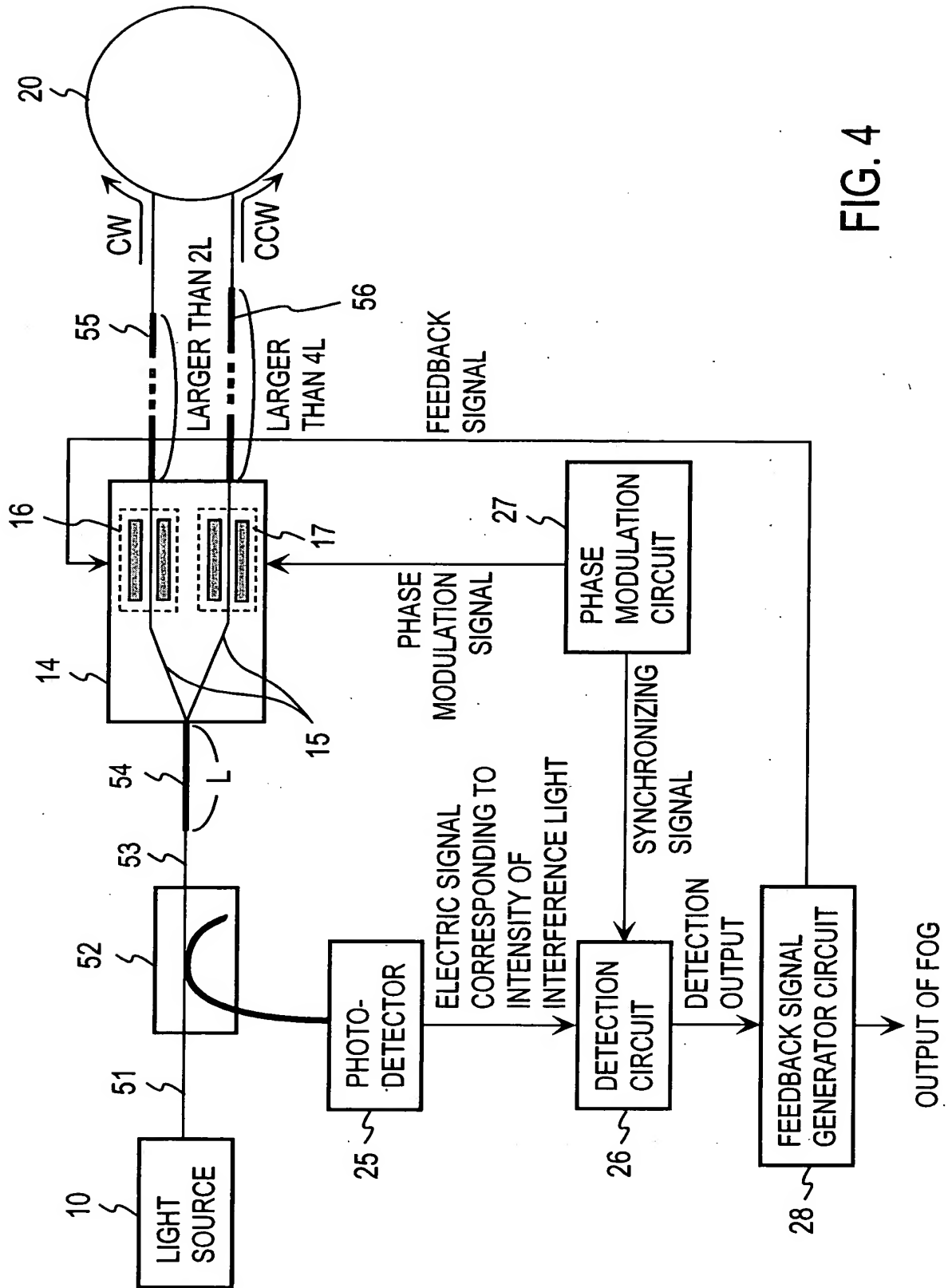
TEMPERATURE TEST IN CASE OPTICAL PATH FROM LIGHT SOURCE TO OPTICAL
 INTEGRATED CIRCUIT IS FORMED BY SINGLE MODE OPTICAL FIBER

FIG. 2



TEMPERATURE TEST IN CASE ALL OF OPTICAL PATH FROM LIGHT SOURCE TO
 OPTICAL INTEGRATED CIRCUIT IS FORMED BY POLARIZATION MAINTAINING
 OPTICAL FIBER

FIG. 3



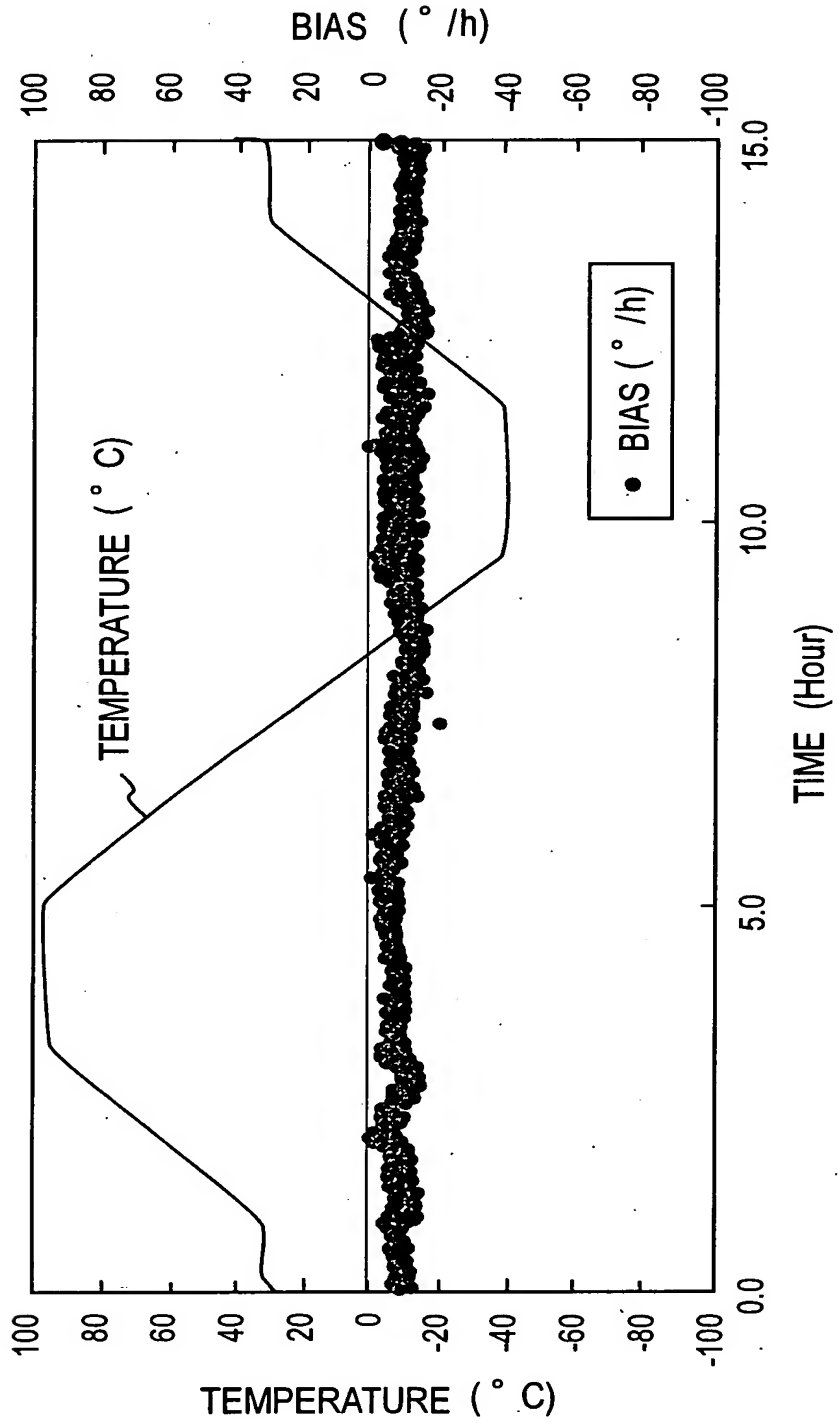
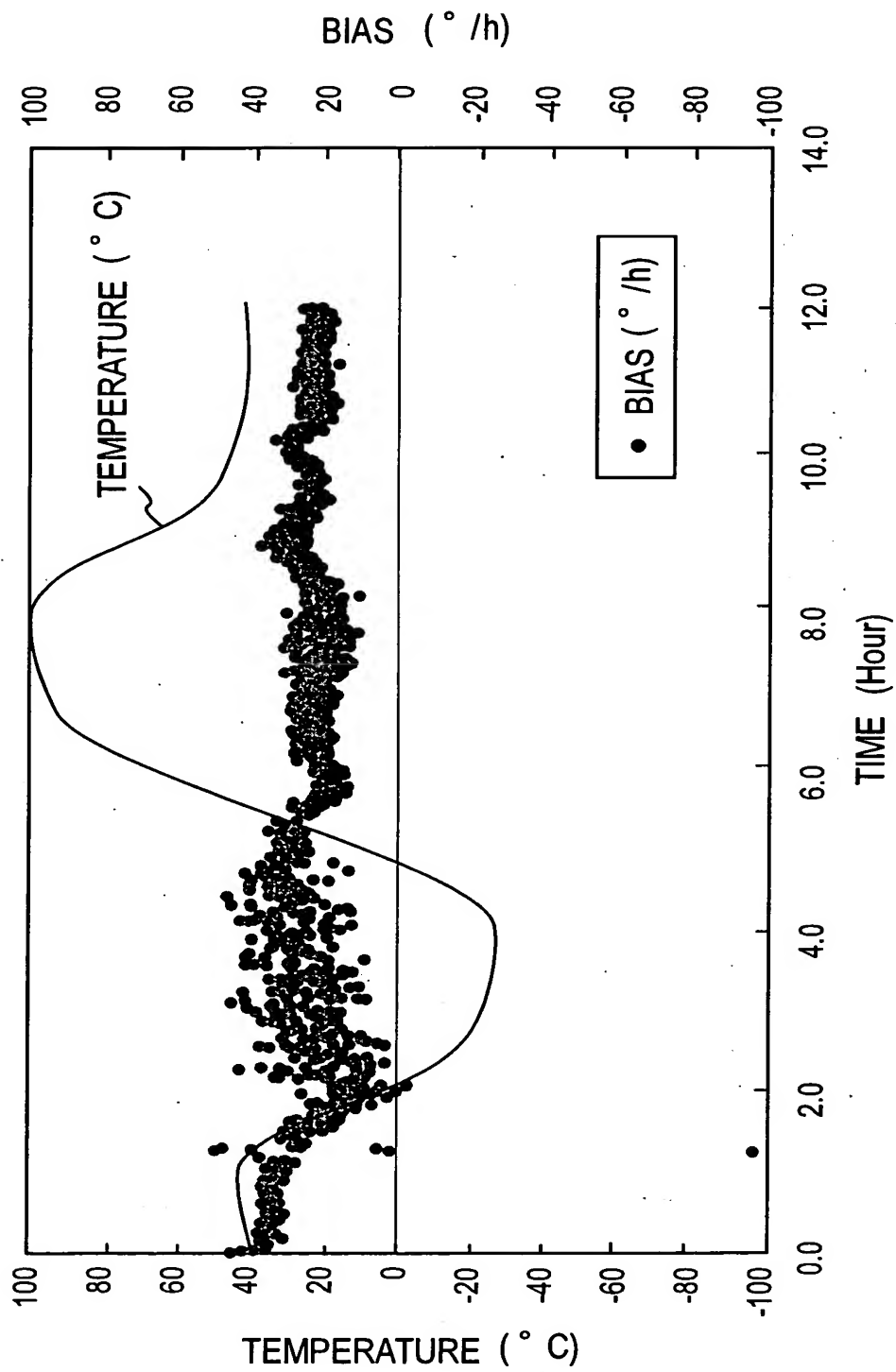


FIG. 5

TEMPERATURE TEST



TEMPERATURE TEST IN CASE A PORTION OF OPTICAL PATH
 FROM LIGHT SOURCE TO OPTICAL INTEGRATED CIRCUIT IS
 FORMED BY POLARIZATION MAINTAINING OPTICAL FIBER
 OF INSUFFICIENT SHORT LENGTH

FIG. 6